

<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	Patty Docket No. LAM1P136/P0602	Application No. 09/539,313
	Applicant: HUANG et al. Filing Date March 30, 2000	Group 2755

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**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

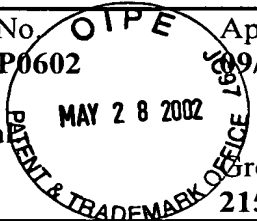
**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J							
	K							
	L							
	M							
	N							

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
<i>De</i>	O	U.S. Patent Application No. 09/539,312, filed March 30, 2000, entitled: "Integrated Full Wavelength Spectrometer for Wafer Processing"
	P	
	Q	
Examiner <i>David England</i>	Date Considered <i>3/31/03</i>	

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	Atty Docket No. <b>LAM1P136/P0602</b> Applicant: <b>HUANG et al</b> Filing Date <b>03/30/00</b>	Application No.: <b>2009/539,313</b>  Group <b>2152</b>
		

### U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
	B						
	C						
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### Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
<i>DE</i>	J	99 08168 A	18/02/99	WIPO	G05B	23/02	Yes	
<i>DE</i>	K	2 692 701	24/12/93	France	G06F	15/46		No
<i>DE</i>	L	0552 873 A1	28/07/93	EPO	G06F	13/40	Yes	
	M							
	N							

### Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
<i>DE</i>	O	International Search Report, date mailed April 19, 2002
<i>DE</i>	P	Kang B. Lee and Richard D. Schneeman, "Internet-Based Distributed Measurement and Control Applications", IEEE Instrumentation & Measurement Magazine, June 1999, pg. 23-27
	Q	
Examiner <i>David England</i>	Date Considered <i>3/31/03</i>	

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